

Power MOSFET

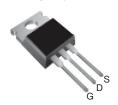
PRODUCT SUMMARY						
V _{DS} (V)	850	850				
R _{DS(on)} (Ω)	V _{GS} = 10 V	2.7				
Q _g (Max.) (nC)	78	78				
Q _{gs} (nC)	9.6	9.6				
Q _{gd} (nC)	45	45				
Configuration	Sing	Single				

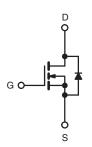
FEATURES

- Halogen-free According to IEC 61249-2-21 **Definition**
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _C = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	850	V	
Gate-Source Voltage			V_{GS}	± 20	7 °	
Continuous Proin Current	V -140V	T _C = 25 °C		4.1		
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C	I _D	2.6	A	
Pulsed Drain Current ^a			I _{DM}	16	1	
Linear Derating Factor				1.0	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	260	mJ	
Avalanche Current ^a			I _{AR}	4.1	Α	
Repetitive Avalanche Energya			E _{AR}	13	mJ	
Maximum Power Dissipation $T_C = 25 ^{\circ}C$			P_{D}	125	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	00	
Soldering Recommendations (Peak Temperature) for 10 s				300 ^d	°C	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque				1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD}=50~V$, starting $T_J=25~^{\circ}C$, L=29~mH, $R_g=25~\Omega$, $I_{AS}=4.1~A$ (see fig. 12). c. $I_{SD}\leq4.1~A$, $dI/dt\leq100~A/\mu s$, $V_{DD}\leq600~V$, $T_J\leq150~^{\circ}C$. d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	-	62	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	-	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	1.0	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		850	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.90	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 800 V, V _{GS} = 0 V	-	-	100	μA
	200		$V_{\rm S} = 0 \text{ V}, T_{\rm J} = 125 ^{\circ}\text{C}$	-	-	500	μ, τ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	$I_D = 2.5 A^b$	-	2.7	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	: 100 V, I _D = 2.5 A	2.5	-	-	S
Dynamic							
Input Capacitance	C_{iss}		$V_{GS} = 0 V$,	-	1300	-	
Output Capacitance	C_{oss}		$V_{DS} = 25 V$,	-	310	-	pF
Reverse Transfer Capacitance	C _{rss}	T = 1	0 MHz, see fig. 5	-	190	-	
Total Gate Charge	Q_g		I _D = 4.1 A, V _{DS} = 400 V, see fig. 6 and 13 ^b	-	-	78	nC
Gate-Source Charge	Q_{gs}	V _{GS} = 10 V		-	-	9.6	
Gate-Drain Charge	Q_{gd}		300 mg. 0 a.na 10	-	-	45	
Turn-On Delay Time	t _{d(on)}	V_{DD} = 400 V, I_{D} = 4.1 A, R_{g} = 12 Ω, R_{D} = 95 Ω, see fig. 10 ^b		-	12	-	ns
Rise Time	t _r			-	33	-	
Turn-Off Delay Time	t _{d(off)}			-	82	-	
Fall Time	t _f			-	30	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	cs						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4.1	А
Pulsed Diode Forward Current ^a	I _{SM}			-	-	16	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 4.1 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 4.1 A, dI/dt = 100 A/μs ^b		-	480	720	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	1.8	2.7	nC
Forward Turn-On Time	t _{on}	Intrinsic tu	on is dor	ninated b	y L _S and	L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

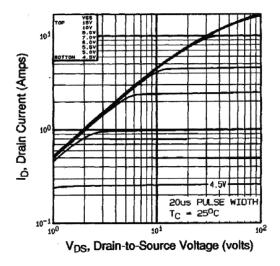


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

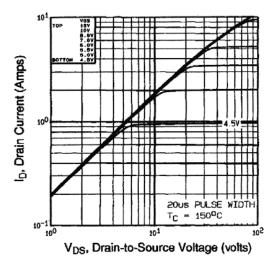


Fig. 2 - Typical Output Characteristics, $T_C = 150 \, ^{\circ}C$

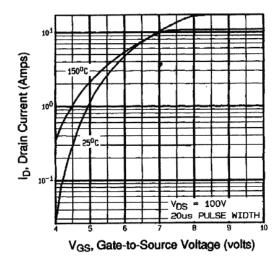


Fig. 3 - Typical Transfer Characteristics

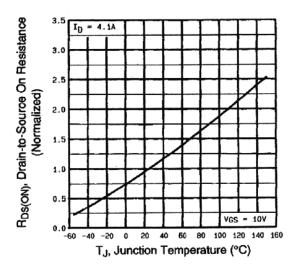


Fig. 4 - Normalized On-Resistance vs. Temperature



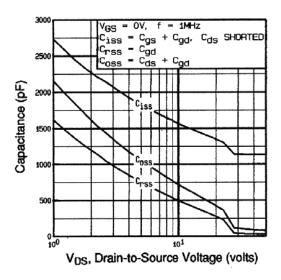


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

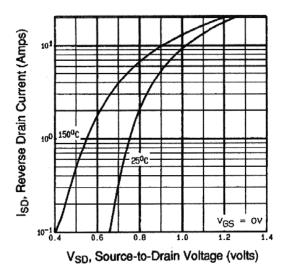


Fig. 7 - Typical Source-Drain Diode Forward Voltage

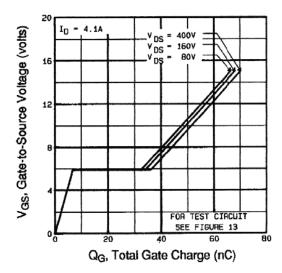


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

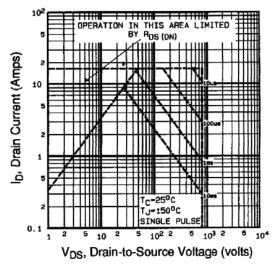


Fig. 8 - Maximum Safe Operating Area



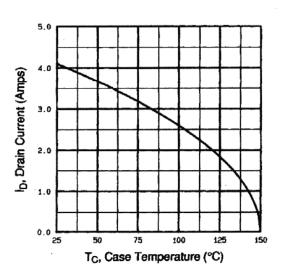


Fig. 9 - Maximum Drain Current vs. Case Temperature

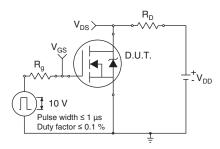


Fig. 10a - Switching Time Test Circuit

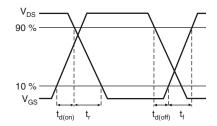


Fig. 10b - Switching Time Waveforms

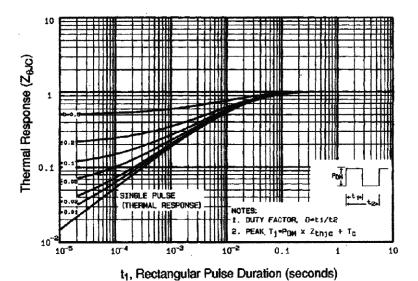


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

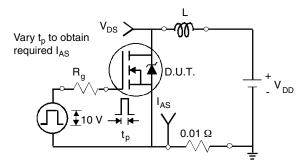


Fig. 12a - Unclamped Inductive Test Circuit

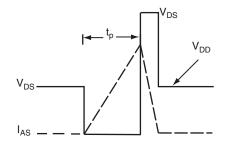


Fig. 12b - Unclamped Inductive Waveforms



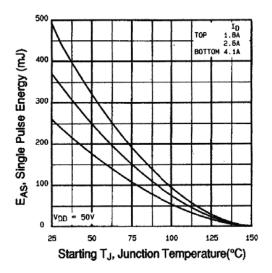


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

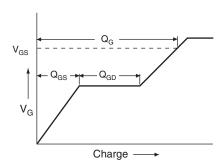


Fig. 13a - Maximum Avalanche Energy vs. Drain Current

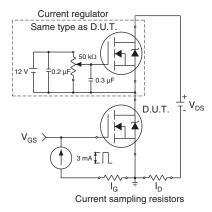
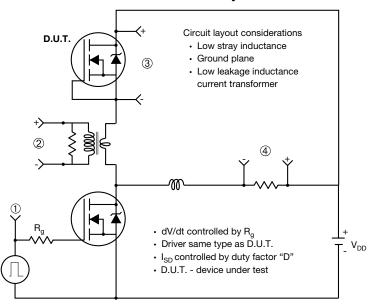


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



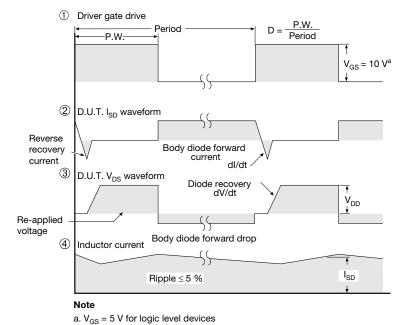
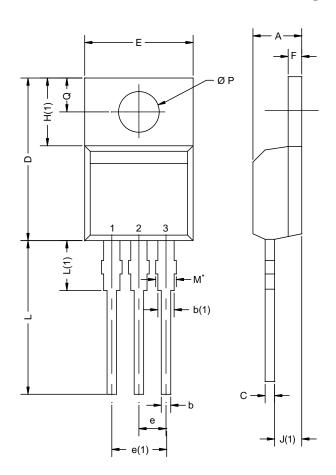


Fig. 14 - For N-Channel



TO-220AB



	MILLIM	IETERS	INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	4.25	4.65	0.167	0.183		
b	0.69	1.01	0.027	0.040		
b(1)	1.20	1.73	0.047	0.068		
С	0.36	0.61	0.014	0.024		
D	14.85	15.49	0.585	0.610		
Е	10.04	10.51	0.395	0.414		
е	2.41	2.67	0.095	0.105		
e(1)	4.88	5.28	0.192	0.208		
F	1.14	1.40	0.045	0.055		
H(1)	6.09	6.48	0.240	0.255		
J(1)	2.41	2.92	0.095	0.115		
L	13.35	14.02	0.526	0.552		
L(1)	3.32	3.82	0.131	0.150		
ØΡ	3.54	3.94	0.139	0.155		
Q	2.60	3.00	0.102	0.118		
ECN: X12-0208-Rev. N, 08-Oct-12						

ECN: X12-0208-Rev. N, 08-Oct-12 DWG: 5471

Notes

 $^{^{\}star}$ M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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